Express Mail Label No. EV 325 215 990 US **FORM PTO-1449** Dock t Number (Optional) **Application Number** 81788.0251 Not Assigned; Parent 10/281-852 INFORMATION DISCLOSURE CITATION **Applicant** FURUKAWA, et al. IN AN APPLICATION (Use several sheets if necessary) Filing Date **Group Art Unit** June 23, 2003 Not Assigned **U.S. PATENT DOCUMENTS EXAMINER** FILING DATE IF **DOCUMENT NUMBER** DATE CLASS NAME **SUBCLASS** INITIAL **APPROPRIATE** 6,404,125 06-2002 Garbuzov et al. 313 499 6,340,824 01-2002 Komoto et al. 257 99 5,998,925 12-1999 Shimizu et al. 313 503 09-1998 5,813,752 Singer et al. 362 293 FOREIGN PATENT DOCUMENTS **Translation** SUBCLASS **DOCUMENT NUMBER** DATE COUNTRY **CLASS** YES NO 2000-082849 03/21/00 **JAPAN** 11-087778 03/30/99 **JAPAN** 10-012916 JAPAN 01/16/98 OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.) Thick GzN Epitaxial Growth with Low Dislocation Density by Hydride Vapor Phase Epitaxy - USUI, et al./ Japanese Journal of Applied Physics 36, Part 2, No. 7B, L899 (1997)

EXAMINER	5-mul	//orm	DATE CONSIDERED	12/14/03	

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.